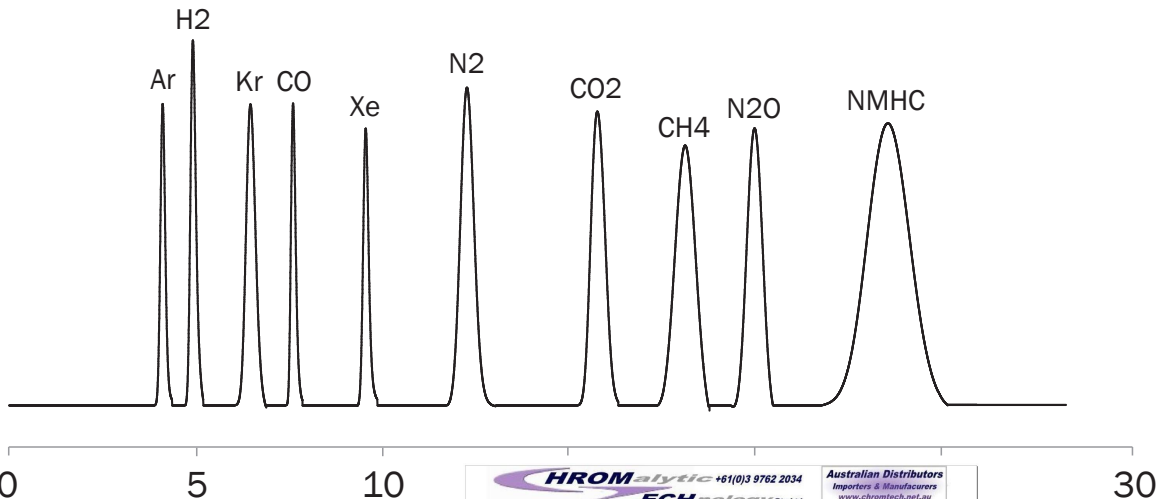


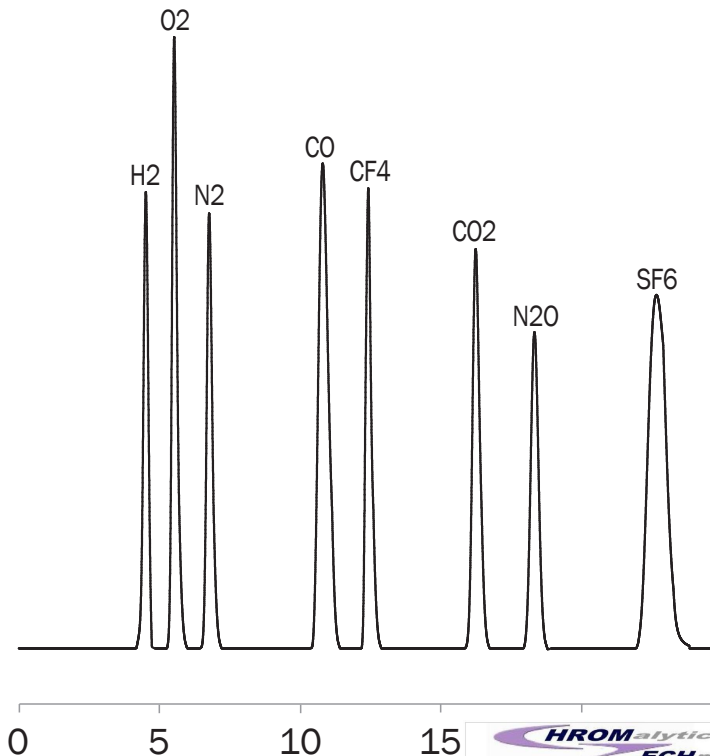
CHROMATOGRAM #80

- Application: Trace impurities at low ppb in Oxygen for semiconductor industry
- Instrument : MultiDetek2 compact GC
- Detector : PlasmaDetek2
- Carrier Gas : Helium

- Impurities :
 - Ar : 796 ppb
 - H2 : 795 ppb
 - Kr : 794 ppb
 - CO : 802 ppb
 - Xe : 796 ppb
 - N2 : 802 ppb
 - CO2 : 799 ppb
 - CH4 : 802 ppb
 - N2O : 798 ppb
 - NMHC : 798 ppb
- Sample : Oxygen



CHROMATOGRAM #81



- Application:
Trace impurities in WF₆
- Instrument :
MultiDetek2 compact GC
- Detector : PlasmaDetek2
- Carrier gas : Helium
- Impurities :
H₂ : 3.23 ppm
O₂ : 4.11 ppm
N₂ : 3.10 ppm
CO : 4.50 ppm
CF₄ : 4.56 ppm
CO₂ : 3.87 ppm
N₂O : 2.33 ppm
SF₆: 5.1 ppm
- Sample :
Tungsten hexafluoride (WF₆)

